

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5082-DIV2	PRIORITY SERIAL NO. 10/297,001			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Jianxing Li et al.				
				PRIORITY FILING DATE November 26, 2002		PRIORITY GROUP 2812		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
CX	AA	6,024,847	02-2000	Rosenberg et al.				
CX	AB	2,949,357	08/1960	Resnick				
CX	AC	5,939,788	08/1999	McTeer				
CX	AD	4,903,117	02/1990	Okamoto et al.				
CX	AE	5,171,379	12/1992	Kumar et al.				
CX	AF	5,403,458	04/1993	Hartig et al.				
CX	AG	5,209,835	05/1993	Makino et al.				
CX	AH	6,521,173	02/2003	Kumar et al.				
CX	AI	5,372,659	12/1994	Lamaze et al.				
CX	AJ	4,830,665	05/1989	Winaad				
CX	AK	5,110,637	05/1992	Ando				
CX	AL	6,451,402	09-2002	Nec				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
CX	AM	JP1092338	04/1989	Japan				
CX	AN	GB 810533	03/1959	Great Britain				
CX	AO	JP57019372	02/1982	Japan				
CX	AP	JP200273623	10/2000	Japan				
CX	AQ	SU1582683	09/1996	SU				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
CX	AR		Hughes et al., "Grain Subdivision and the Development of Local Orientations in Rolled Tantalum" Tantalum, The Minerals, Metals & Materials Society, 1996, pgs. 257-262. (Year is sufficiently early so that the month is not an issue.)					
CX	AS		Arlt, Jr., "Sulfonation and Sulfonation to Thorium and Thorium Compounds" Kirk-Othmer Encyclopedia of chemical Technology vol. 22, pp. 541-564, (1993, Year is sufficiently early so that the month is not an issue).					
CX	AT		Kirkbride et al., "The Effect of Yttrium on the Recrystallization and Grain Growth of Tantalum", J. Less-Common Metals, vol. 9, pp. 393-408, 1965. (Year is sufficiently early so that the month is not an issue.)					
EXAMINER <i>Christy Horacek</i>				DATE CONSIDERED 6/8/05				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
CK	AA	6,417,105	07-2002	Shah et al.			
CK	AB	4,895,770	01-1990	Schintlmeister et al.			
CK	AC	6,396,207	05-2002	Hasegawa et al.			

FOREIGN PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
CK	AD	252,442	09.06.1960	Australia			
CK	AE	WO 00/13235	09/03/2000	PCT			
CK	AF	08120445	14/05/1996	Japan			
CK	AG	FR 2 585 730 A1	08/01/1985	France			
CK	AH	GB 2 202 237 A	21/09/1988	GB			
CK	AI	55-179784	12-1980	Japan			
CK	AJ	2000012539	14/01/2000	Japan			
CK	AK	JP 11074348	03/1999	Japan			
CK	AL	5-255843	10-1993	Japan			
CK	AM	05097408	04-1993	Japan			
CK	AN	0 928 977 A1	07-1999	EP			
CK	AO	JP61031992A	02-1986	Japan			
CK	AP	0 442 752 A1	08-1991	EP			

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)		
CK	AQ	National Research Corporation Press Release, pgs. 1-4, July 1964.
CK	AR	National Research Corporation Data Sheet "SGS Tantalum", pgs. 1-7, no date.
CK	AS	ASTM Standard Specification for Tantalum and Tantalum Alloy Plate, Sheet, and Strip, pgs. 558-561, 1992. (Year is sufficiently early so that the month is not an issue.)
CK	AT	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Materials Research Society Symposium Proceedings, vol. 322, pgs. 413-422, 1994. (Year is sufficiently early so that the month is not an issue.)
CK	AU	Clark et al., "Influence of Transverse Rolling on the Microstructural and Texture Development in Pure Tantalum", Metallurgical Transactions, vol. 23A, pgs. 2183-2191, August 1992.
CK	AV	Raabe, et al., "Texture and Microstructure of Rolled and Annealed Tantalum", Materials Science and Technology, Vol. 10, pgs. 299-305, April 1994.
CK	AW	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Refractory Metals & Hard Materials, vol. 12, pgs. 35-40, 1994. (Year is sufficiently early so that the month is not an issue.)
CK	AX	Klein et al., "Inhomogeneous Textures in Tantalum Sheets" Materials Science Forum, vol. 157-162, pgs. 1423, (1994). (Year is sufficiently early so that the month is not an issue.)


  

EXAMINER <i>Christy Horvack</i>	DATE CONSIDERED 6/8/05
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<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT Jianxing Li et al.			
				PRIORITY FILING DATE November 26, 2002	PRIORITY GROUP 2812		
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	<del>60055310</del>	<del>08-2000</del>	<del>Li et al.</del>			
	AB						
	AC						
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes    No
CH	AD	WO 02/00959A1	01-2002	PCT			
CH	AE	09-625562	01-1997	Japan			
CH	AF	56-71955	06-1981	Japan			
CH	AG	02-173222	07-1990	Japan			
CH	AH	EP0872572A1	10-1998	EP			
CH	AI	WO 98/49357	11-1998	PCT			
	AJ						
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
CH	AQ		Wright et al., "Texture Gradient Effects in Tantalum", International Conference on Textures of Materials, 7 pgs., September 1993.				
CH	AR		Wright et al., "Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate", Metallurgical Transactions A, 25A (1994), pgs. 1-17. (Year is sufficiently early so that the month is not an issue.)				
CH	AS		Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047).				
CH	AT		Kumar et al., "Corrosion Resistant Properties of Tantalum" Corrosion 95, Paper No. 253, 14 pages. (No date)				
CH	AU		Knotek et al., "The Structure and Composition of Ti-Zr-N, Ti-Al-Zr-N and Ti-Al-V-N Coatings" Materials Science and Engineering, A105/106, December 1988, pgs. 481-488.				
CH	AV		Sakamoto et al., "Preparation and Microstructure of Reactively Sputtered Ti <sub>1-x</sub> Zr <sub>x</sub> N Films" Thin Solid Films 228, May 1993, pgs. 169-172.				
EXAMINER <i>Christy Horvacek</i>				DATE CONSIDERED 6/8/05			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5083-TN1V2		SERIAL NO. 10783,247		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Jardine JJ et al.				
				FILING DATE February 19, 2004		GROUP 2822		
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
CK	AA	6,176,944 B1	01-2001	Shenoy et al.				
CK	AB	6,008,354	05-2000	Rosenberg et al.				
CK	AC	4,189,358	02-1990	Scarpellino Jr. et al.				
CK	AD	US2004/0023960A1	03-2004	Perry et al.			Aug. 8, 2002	
CK	AE	US2004/0011432A1	01-2004	Pudlaka et al.			Jul. 17, 2002	
	AF							
	AG							
	AH							
	AI							
	AJ							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AK	363014864A	01-1988	Japan (abstract only)				
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Portion Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
Christy Horacek				6/8/05				
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Form PTO-1449				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5082-DIV2		SERIAL NO. 10/783,247		
LIST OF ART CITATIONS BY APPLICANT (Use several citations if necessary)						APPLICANT Jianxing Li et al.				
						FILING DATE February 19, 2004		PRIORITY GROUP 2812		
U.S. PATENT DOCUMENTS										
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate				
OK	AA	6,210,634 B1	04-2001	Ishigami et al.	420	417				
	AB									
	AC									
	AD									
	AE									
	AF									
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	AH									
	AI									
	AJ									
	AK									
	AL									
FOREIGN PATENT DOCUMENTS										
	Document Number	Date	Country	Class	Subclass	Translation				
						Yes	No			
OK	AM	08-255912	01.10.1996	Japan		X				
	AN									
	AO									
	AP									
	AQ									
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)										
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EXAMINER <i>Christy Samuels</i>				DATE CONSIDERED 6/8/05						
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5097-DIV2		SERIAL NO. 10789247	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Hanzheng Li et al.			
				FILING DATE February 19, 2004		GROUP 2537	
U.S. PATENT DOCUMENTS							
*Examiner (Initial)	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
CH	AA	6,559,573	05-2003	Hovda et al.			
CH	AB	6,482,302 M1	11-2002	Li et al.			
CH	AC	6,723,187 B2	04-2004	Segal et al.			
CH	AD	2003/0132106 A1	07-2003	Takshadi et al.			Jan. 14, 2003
	AE						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
	AP						
	AQ						
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	AS						
	AT						
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